

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	13	(window same mask\$3 same pattern same match\$3 same template\$1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:25
L2	2	1 and partial\$3 near2 match\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:28
L3	130	partial\$3 near2 template\$1 same match\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:29
L4	23	3 and mask\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:30
L5	18	4 and pixel\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:30

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L1	149	window same mask\$3 same pattern same match\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:51
L2	13	1 same template\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:55
L3	13	2 and match\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:06
L4	3465	partial\$3 near match\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:07
L5	400	4 same (bit\$1 or pixel\$1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:08
L6	156	5 same (mask\$3 or template\$1 or window\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:09
L7	60	6 same enhanc\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:10

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L8	1	7 same (target or center or interest)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:10
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IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **Performance optimization using template mapping for datapath-intensive synthesis**
Corazao, M.R.; Khalaf, M.A.; Guerra, L.M.; Potkonjak, M.; Rabaey, J.M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction:
Volume 15, Issue 8, Aug. 1996 Page(s):877 - 888
Digital Object Identifier 10.1109/43.511568
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- ☐ 2. **Optical recognition of handwritten Chinese characters by partial matching**
Wang, A.-B.; Huang, J.S.; Fan, J.-C.;
Document Analysis and Recognition, 1993., Proceedings of the Second International
Conference on
20-22 Oct. 1993 Page(s):822 - 823
Digital Object Identifier 10.1109/ICDAR.1993.395611
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- ☐ 3. **Object matching on irregular pyramid**
Paillancy, J.-G.; Kropatsch, W.; Jolion, J.-M.;
Pattern Recognition, 1998. Proceedings. Fourteenth International Conference,
Volume 2, 16-20 Aug. 1998 Page(s):1721 - 1723 vol.2
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- ☐ 4. **Surface signatures: an orientation independent free-form surface representation for the purpose of objects registration and matching**
Yamany, S.M.; Farag, A.A.;
Pattern Analysis and Machine Intelligence, IEEE Transactions on
Volume 24, Issue 8, Aug. 2002 Page(s):1105 - 1120
Digital Object Identifier 10.1109/TPAMI.2002.1023806
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(6059 KB\)](#) IEEE JNL
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- ☐ 5. **Progressive coding of palette images and digital maps**
Forchhammer, S.; Salinas, J.M.;
Data Compression Conference, 2002. Proceedings. DCC 2002

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Digital Object Identifier 10.1109/DCC.2002.999974

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- ☐ 6. **Free-form surface registration using surface signatures**
Yamany, S.M.; Farag, A.A.;
Computer Vision, 1999. The Proceedings of the Seventh IEEE International C
Volume 2, 20-27 Sept. 1999 Page(s):1098 - 1104 vol.2
Digital Object Identifier 10.1109/ICCV.1999.790402
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☐ 7. **Instruction set mapping for performance optimization**
Corazao, M.; Khalaf, M.; Guerra, L.; Potkonjak, M.; Rabaey, J.;
Computer-Aided Design, 1993. ICCAD-93. Digest of Technical Papers., 1993 I
International Conference on
7-11 Nov. 1993 Page(s):518 - 521
Digital Object Identifier 10.1109/ICCAD.1993.580107
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☐ 8. **Photo time-stamp detection and recognition**
Xiangrong Chen; Hong-Jiang Zhang;
Document Analysis and Recognition, 2003. Proceedings. Seventh Internationa
3-6 Aug. 2003 Page(s):319 - 322 vol.1
AbstractPlus | Full Text: PDF(296 KB) IEEE CNF
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